## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE.

Applicants: Ismail Kashkoush Examiner: Lan Vinh

Serial No.: 10/585,229 Art Unit: 1713

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FOT: SYSTEM AND METHOD FOR SELECTIVE ETCHING OF SILICON NITRIDE DURING SUBSTRATE

PROCESSING

## RESPONSE TO RESTRICTION REQUIREMENT

In response to the restriction requirement dated September 3, 2010, Applicant hereby elects <u>without traverse</u> Group I, which is drawn to a method for selective etching of silicon nitride during substrate processing and encompasses claims 1-12 and 22.

The Belles Group, P.C.

Brian J. Bollam

Date: October 4, 2010

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